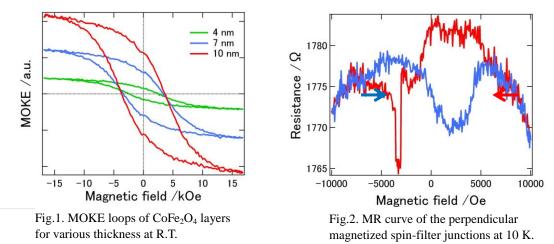
Fabrication of perpendicular magnetized spin-filter junctions using ferromagnetic insulator CoFe₂O₄

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[Introduction] The generation of highly spin-polarized electron currents is one of the dominant focuses in the field of spintronics. A spin-filter junction with a ferromagnetic insulator is potential candidate for practical spin-polarized current sources. Many investigations have been carried out on the development of in-plane magnetized spin-filter junctions using ferromagnetic insulator $CoFe_2O_4$ ^[1]. On the other hand, several studies have reported that the $CoFe_2O_4$ films have the perpendicular magnetic anisotropy induced by lattice strain on MgO(100) substrate^[2]. In this work, we fabricated the perpendicular magnetized spin-filter junctions using CoFe₂O₄ and investigated the magnetotransport properties.

[Experiment] The perpendicular magnetized spin-filter junctions were prepared by reactive MBE method. Sample structures were MgO(100) /Cr(20 nm) /Pt(10 nm) / CoFe₂O₄ (3-7 nm) /MgO(2 nm) / FePt(10 nm)/Au(30 nm). CoFe₂O₄ thin films were deposited at 300°C in the oxygen radical atmosphere of 4×10^{-4} Pa and annealed at 450°C. FePt films were prepared from individual Fe and Pt sources at 500°C. The epitaxial growth and surface structures were observed by RHEED and AFM. The magnetic properties were measured by MOKE at RT. The films were patterned into 10 x 10 µm² devices with photolithography, Ar ion milling and sputtering.

[Results] Fig.1 shows MOKE loops of $CoFe_2O_4$ layers for various thickness. The magnetic field was applied perpendicular to the film plane. The films showed clear perpendicular magnetic anisotropy. The RHEED of $CoFe_2O_4$ was clear streak pattern and the Root Mean Square(RMS) was estimated as 0.29 nm from AFM measurements. Fig.2 shows a MR curve of the perpendicular magnetized spin-filter junctions at 10 K with a bias of 0.3 V. The MR curve of -1.1% was observed.



[1] Y. K. Takahashi et al., Appl. Phys. Lett. 96, 072512(2010).

[2]H. Yanagihara et al., J Appl. Phys., 109, 07C122(2011).